

Rigaku Debuts High-performance, Direct Excitation Variable Spot EDXRF Elemental Analyzer at Pittcon 2016

Rigaku will be in attendance at Pittcon 2016, introducing its new benchtop variable spot EDXRF spectrometer at Booth #1318

March 7, 2016 – Tokyo, Japan. [Applied Rigaku Technologies](http://www.rigaku.com), Inc. has announced its launch of the new [Rigaku NEX DE VS](#) direct excitation variable spot X-ray fluorescence (EDXRF) elemental analyzer. The instrument is debuting at the 66th annual Pittsburgh Conference on Analytical Chemistry and Applied Spectroscopy ([Pittcon 2016](#)), held Sunday, March 6, 2016 through Thursday, March 10, 2016 at the Georgia World Congress Center in Atlanta, GA USA.

The NEX DE VS analyzer is the newest addition to the Rigaku NEX DE Series of high-performance, direct excitation EDXRF elemental analyzers.

Each instrument in the NEX DE series is equipped with a 60 kV, 12 W X-ray tube and a high-throughput Si drift detector. This detector supports count rates in excess of 500K cps, resulting in low limits of detection. The instruments were designed for demanding applications or for situations where analysis time or sample throughput is critical, and is suitable for a broad range of applications, including exploration, research, bulk RoHS inspection, and education, as well as industrial and production monitoring applications.



Rigaku NEX DE VS - Variable Spot Energy Dispersive X-ray Fluorescence Spectrometer

The screenshot shows the NEX software interface with the following details:

- Sample changer:** DE-None Atmosph
- Position:** 1
- Application:** RoHS Polymer 1mm, RoHS Polymer 3mm, Solder 1mm, Metals
- Memo:** Sample name: Doll Eye Paint, Analyzed By: John Smith, Report No.: 14a, Company: Doll Co., Analysis group: 15, Part No.: 14423, Sample Weight: 145g, Material: PE, Result output: File name: Doll Eye Paint
- Table:**

Position	Type	Application	Sample name	File name	Completion time
1	EMP analysis	RoHS Polymer 1mm	Doll Eye Paint	Doll Eye Paint	3:23 PM
- Result Display:**

Component	Cr	Hg	Pb	Br	Cd
Unit	mass%	mass%	mass%	mass%	mass%
Result	ND	ND	ND	ND	ND

Point Analysis interface, available in a variety of languages, is used for small spot measurements. A live camera display is shown in the left window.

The NEX DE VS analyzer is uniquely suited for small spot analysis applications. It features a high-resolution camera combined with automated collimators allowing for precise positioning of a sample for the analysis of 1 mm, 3 mm, and 10 mm spot sizes. These features, combined with the advanced Rigaku QuantEZ analytical software, provide unparalleled performance for both bulk and small spot analysis in a single instrument.

The NEX DE VS spectrometer is on display at PITTCON 2016 at Booth #1318.

About Rigaku

Since its inception in Japan in 1951, Rigaku has been at the forefront of analytical and industrial instrumentation technology. Rigaku and its subsidiaries form a global group focused on general-purpose analytical instrumentation and the life sciences. With hundreds of major innovations to their credit, Rigaku companies are world leaders in X-ray spectrometry, diffraction, and optics, as well as small molecule and protein crystallography and semiconductor metrology. Today, Rigaku employs over 1,100 people in the manufacturing and support of its analytical equipment, which is used in more than 70 countries around the world supporting research, development, and quality assurance activities. Throughout the world, Rigaku continuously promotes partnerships, dialog, and innovation within the global scientific and industrial communities.

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